

IEEE Home | Search IEEE | Shop | Web Account | Contact IEEE

Membership Publications Services Standards Conferences Careers/Jobs



United States Patent and Trademark Office

Help | FAQ | Terms | IEEE Peer Review

Quick Links

IEEE Xplore Database

- Home
- What Can I Access?
- Log Out

Your search matched 3 of 987057 documents.
Results are shown 15 to a page, sorted by publication year in descending order.

Results:
Journal or Magazine = **JNL** Conference = **CNF** Standard = **STD**

1 Short cycle killer-particle control based on accurate in-line defect classification

Shimoda, A.; Watanabe, K.; Takagi, Y.; Maeda, S.; Semiconductor Manufacturing, 2000. Proceedings of ISSM 2000. The Ninth International Symposium on, 26-28 Sept. 2000
Page(s): 199 -202

[Abstract] [PDF Full-Text (481 KB)] **IEEE CNF**

2 A new auto-lock circuit concept guaranteeing low jitter in PLL frequency synthesizers irrespective of process variations

O'Sullivan, E.; Kawaguchi, M.; Shimoda, A.; Bipolar/BiCMOS Circuits and Technology Meeting, 1996., Proceedings of the 1996, 29 Sept.-1 Oct. 1996
Page(s): 220 -223

[Abstract] [PDF Full-Text (396 KB)] **IEEE CNF**

³ A new multi-beam radar signal processor

Hara, Y.; Kaneko, T.; Obata, Y.; Shimoda, A.; Yamaguchi, H.; Sugimoto, T.; Saito, J.; Iijima, N.; Ueda, Y.; Fujisaka, T.; Kondo, M.; Mizuno, M.; Radar Conference, 1995., Record of the IEEE 1995 International, 8-11 May 1995

Page(s): 207 -212

[\[Abstract\]](#) [\[PDF Full-Text \(588 KB\)\]](#) **IEEE CNF**

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#)
[Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#)
[No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2003 IEEE — All rights reserved